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ATTONIA	COMEINA	ET NO. I	ATTORNEY DOCKE	AMED INVENTOR	FIRST NA	PLICATION NO. FILING DATE		APPLICATION NO.	
ATION NO.	CONFIRMA	ET NO.			D.	06/27/2003		10/609,306	
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	INER	EXAMIN				Agfa Corporation Law & Patent Department			
	, JOSEPH P	RTINEZ, J	MAI		,				
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IUMBER	PAPER N	<u> </u>	ART UNIT			1887-1069	MA 018	Wilmington, M	
			2873			1005			
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Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)
055	10/609,306	COMEAU ET AL.
Office Action Summary	Examiner	Art Unit
	Joseph P. Martinez	2873
The MAILING DATE of this commu. Period for Reply	nication appears on the cover sheet w	ith the correspondence address
- Topiy		
A SHORTENED STATUTORY PERIOD IN THE MAILING DATE OF THIS COMMUN - Extensions of time may be available under the provision after SIX (6) MONTHS from the mailing date of this come of the period for reply specified above is less than thirty (1) If NO.period for reply is specified above, the maximum self-allure to reply within the set or extended period for reply Any reply received by the Office later than three months earned patent term adjustment. See 37 CFR 1.704(b).	NICATION. Is of 37 CFR 1.136(a). In no event, however, may a rimunication. (30) days, a reply within the statutory minimum of third statutory period will apply and will expire SIX (6) MON	reply be timely filed by (30) days will be considered timely. THS from the mailing date of this communication.
tatus		
1) Responsive to communication(s) file	ed on	
	2b)⊠ This action is non-final.	*
	for allowance except for formal matte	ers prosecution as to the morita in
closed in accordance with the pract	ice under Ex parte Quayle, 1935 C.D	11 453 O C 212
•	- Pario Gadyio, 1900 O.D	. 11, 1 00 O.G. 213.
isposition of Claims	*	
4) Claim(s) 1-17 is/are pending in the	application.	
4a) Of the above claim(s) is/a		
5) Claim(s) is/are allowed.	* *	
6)⊠ Claim(s) <u>1-17</u> is/are rejected.		
7) Claim(s) is/are objected to.		
8) Claim(s)are subject to restrict		of the second second second
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pplication Papers		r .
9) The specification is objected to by th	e Examiner.	•
10)⊠ The drawing(s) filed on 08 April 2004	is/are: a)⊠ accepted or b)⊡ objec	ted to by the Examiner
Applicant may not request that any obje	ction to the drawing(s) be held in abeyand	ce. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including	the correction is required if the drawing(s) is objected to See 37 CFR 1 121(d)
11) The oath or declaration is objected to	by the Examiner. Note the attached	Office Action or form PTO-152
		102.
iority under 35 U.S.C. § 119	- -	·
12) Acknowledgment is made of a claim	for foreign priority under 35 U.S.C. §	119(a)-(d) or (f).
a)∐ All b)∐ Some * c)∏ None of:		
1. Certified copies of the priority	documents have been received.	
2. Certified copies of the priority	documents have been received in Ap	plication No.
3. Copies of the certified copies	of the priority documents have been r	eceived in this National Stage
application from the Internation	nal Bureau (PCT Rule 17.2(a)).	
* See the attached detailed Office action	n for a list of the certified copies not re	eceived.
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achment(s)	•	
Notice of References Cited (PTO-892)	4) 🔲 Interview Su	mmary (PTO-413)
Notice of Draftsperson's Patent Drawing Review (P	TO-948) Paper No(s)/	/Mail Date ormal Patent Application (PTO-152)
	CONTRACTOR SILL NOTICE OF INF	ormal Patent Application (PTO-152)
Information Disclosure Statement(s) (PTO-1449 or I Paper No(s)/Mail Date	6) Other:	

DETAILED ACTION

Claim Rejections - 35 USC § 102

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claims 1-2 and 6-7 are rejected under 35 U.S.C. 102(a) as being fully anticipated by Kruschwitz et al. (6479811).

Re claims 1 and 6, Kruschwitz et al. teaches for example in fig. 6, an illumination modulator correction system for adjusting the operational parameters of an illumination modulator in an imaging system, said correction system comprising: modulator pattern generation unit (64) for providing a test pattern on the illumination modulator (col. 7, ln. 30-32 and col. 8, ln. 64-66); modulator adjustment unit (78) for permitting an actuation voltage on said illumination modulator to be changed through a range of actuation voltage values (col. 7, ln. 60-62); a detector (76) for receiving a modulated illumination field in at least a first region from said illumination modulator in a first direction (col. 7, ln. 46-49); sampling unit (82, wherein the office interprets the sampling unit and evaluation unit to be an integral unit as taught by Kruschwitz et al.) for determining at least one sample value for at least one area or one region of said modulated illumination field (col. 8, ln. 2-6); and evaluation unit (82, wherein the office interprets the sampling unit and evaluation unit to be an integral unit as taught by Kruschwitz et al.) for determining a minimum or optimal sample value (col. 7, ln. 3-13) within said range of actuation voltage values of said illumination modulator (col. 8, ln. 2-6).

Re claims 2 and 7, Kruschwitz et al. further teaches for example in fig. 6, said system further includes adjustment unit (78) for adjusting the actuation voltage of said illumination modulator responsive to said evaluation unit (col. 7, ln. 60-65).

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Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 3-5 and 8-17 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kruschwitz et al. (6479811).

Re claims 3, 8 and 12, Kruschwitz et al. teaches for example in fig. 6, an illumination modulator correction system for adjusting the operational parameters of an illumination modulator in an imaging system, said correction system comprising: modulator pattern unit (64) for providing a test pattern on the illumination modulator over a first area in a first direction (col. 7, ln. 30-32 and col. 8, ln. 64-66); modulator adjustment unit (78) for permitting an actuation voltage on said illumination modulator to be changed through a range of actuation voltage values (col. 7, ln. 60-62); a detector (76) for receiving a modulated illumination field from said illumination modulator in said first direction (col. 7, ln. 46-49); sampling unit (82, wherein the office interprets the sampling unit and evaluation unit to be an integral unit as taught by Kruschwitz et al.) for determining an average sample value for each of said regions of said modulated illumination field (col. 8, ln. 2-6); and evaluation unit (82, wherein the office interprets the sampling unit and evaluation unit to be an integral unit as taught by Kruschwitz et interprets the sampling unit and evaluation unit to be an integral unit as taught by Kruschwitz et

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al.) for determining an optimal sample value (col. 7, ln. 3-13) within said range of activation voltage values of said illumination modulator (col. 8, ln. 2-6).

But, Kruschwitz et al. fails to explicitly teach a first region, a second region and a third region.

However, Kruschwitz et al. teaches the use of a segmented detector to "monitor the intensity of the light diffracted from each pixel" (col. 7, ln. 54-56) and further that the image from each pixel "covers one or more segments of the segmented detector" (col. 7, ln. 51-54).

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to provide three sample values for three areas as claimed, since it has been held that discovering an optimum value of a result effective variable involves only routine skill in the art. *In re Boesch*, 617 F.2d 272, 205 USPQ 215 (CCPA 1980).

Furthermore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the teachings of Kruschwitz et al. to provide three sample values for three areas in order to provide a spatially uniform diffracted intensity profile or constant output power (col. 8, ln. 5-9).

Re claim 13, Kruschwitz et al. further teaches for example in fig. 6, said system further includes adjustment unit (78) for adjusting the actuation voltage of said illumination modulator responsive to said evaluation unit (col. 7, ln. 60-65).

Re claims 4-5, 9-11 and 14-17, Kruschwitz et al. further teaches for example, minimum sample value is determined at a rollover point for one of said sample values in the central region

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of said first area (col. 7, ln. 54-56, wherein the office interprets the teachings of monitoring intensity of each pixel to include a central region of the first area) or responsive to a second rollover point for said sample values (η_0 and η_1 , col. 7, ln. 3-13, wherein the office interprets the teachings of Kruschwitz et al. to include at least two rollover points calculated going from minimum to maximum and from maximum to minimum) or said optimal value is determined responsive to a rollover point having a minimal energy value for said sample values (col. 7, ln. 3-13).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Joseph P. Martinez whose telephone number is 571-272-2335. The examiner can normally be reached on M-F 7:00 AM to 3:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Georgia Y. Epps can be reached on 571-272-2328. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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JPM 5-27-04

Georgia Epps
Supervisory Patent Examiner
Technology Center 2800